ANTENNA

ISSUED BY Shenzhen BALUN Technology Co., Ltd.



FOR

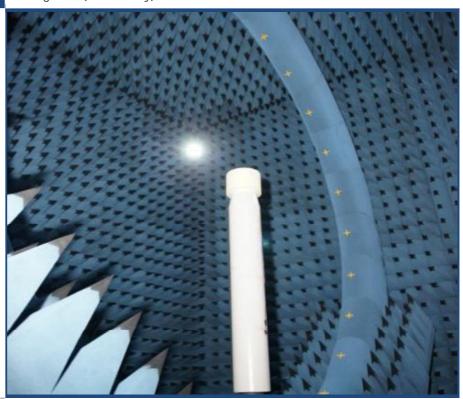
PCB Antenna

ISSUED TO

Guangzhou Super Technology Co., LTD

TESTREPORT

Address:1st Floor, No.65 Fengan 3rd Street, Xinexin Road, Haizhu District, Guangzhou (Office only), Chian



Tested by:

Shang Dandon

Shang Dandan

(Engineer)

Date

Date

Approved by:

milin

Wei Yanquan

(Chief Engineer)

Date

Report No:

BL-EC1950331-902

EUT Name:

PCB Antenna

Model Name:

ANT-2.4G-2

Test Standard:

IEEE149-1979

Maximum:

Gain: 3 (dBi)

Efficiency: 70%

Test Date:

May 23, 2019

Date of Issue:

May 29, 2019

NOTE: This test report of test results only related to the testing samples, which can be duplicated completely for the legal use with the approval of the applicant; it shall not be reproduced except in full, without the written approval of Shenzhen BALUN Technology Co., Ltd. Any objections should be raised within thirty days from the date of issue. To validate the report, please visit BALUN website.



Revision History

Version

Issue Date

Revisions

Rev. 01

May 29, 2019

Initial Issue

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1 Administrative Data (GENERAL INFORMATION)

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Addross	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.	
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,	
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China	
	The laboratory is a testing organization accredited by China National	
	Accreditation Service for Conformity Assessment (CNAS) according to	
Accreditation Certificate	ISO/IEC 17025. The accreditation certificate number is L6791.	
Accreditation Certificate	The laboratory is a testing organization accredited by China Metrology	
	Accreditation (CMA). The accreditation certificate number is	
	2017192290Z.	
	All measurement facilities used to collect the measurement data are	
Description	located at Block B, FL 1, Baisha Science and Technology Park, Shahe	
Description	Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R.	
	China 518055	

1.3 Laboratory Condition

Ambient Temperature	19°C to 25°C
Ambient Relative Humidity	45% to 55%
Ambient Pressure	100 kPa to 102 kPa

1.4 Announce

- (1) The test report reference to the report template version v2.2.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (5) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (6) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	Guangzhou Super Technology Co., LTD
Address	1st Floor, No.65 Fengan 3rd Street, Xinexin Road, Haizhu District, Guangzhou (Office only), China
Telephone Number	N/A
Fax Number	N/A
E-mail Address	N/A

2.2 Manufacturer Information

Manufacturer	N/A
Address	N/A

2.3 Factory Information

Factory	N/A
Address	N/A

2.4 General Description for Equipment under Test (EUT)

EUT Name	PCB Antenna
Model Name Under Test	ANT-2.4G-2
Antenna Type	PCB Antenna
Dimensions	19mm * 5mm
Polarization	Vertical

2.5 Ancillary Equipment

Note: Not applicable.

2.6 Technical Information

Frequency Range	2400MHz ~ 2500MHz
	2400MHz, 2402MHz, 2404MHz, 2406MHz, 2408MHz, 2410MHz,
	2412MHz, 2414MHz, 2416MHz, 2418MHz, 2420MHz, 2422MHz,
	2424MHz, 2426MHz, 2428MHz, 2430MHz, 2432MHz, 2434MHz,
	2436MHz, 2438MHz, 2440MHz, 2441MHz, 2442MHz, 2444MHz,
Test Frequencies	2446MHz, 2448MHz, 2450MHz, 2452MHz, 2454MHz, 2456MHz,
	2458MHz, 2460MHz, 2462MHz, 2464MHz, 2466MHz, 2468MHz,
	2470MHz, 2472MHz, 2474MHz, 2476MHz, 2478MHz, 2480MHz,
	2482MHz, 2484MHz, 2486MHz, 2488MHz, 2490MHz, 2492MHz,
	2494MHz, 2496MHz, 2498MHz, 2500MHz



3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	IEEE149-1979	IEEE Standard Test Procedures for Antennas

3.2 Test Verdict

Report Section	Description	Remark
ANNEX A.1	Gain and Efficiency	-
ANNEX A.2	VSWR	-
ANNEX B	Radiation Pattern	

3.3 Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Item	Uncertainty
VSWR(S11)	±0.2
Gain	± 0.5 dB



4 GENERAL TEST CONFIGURATIONS

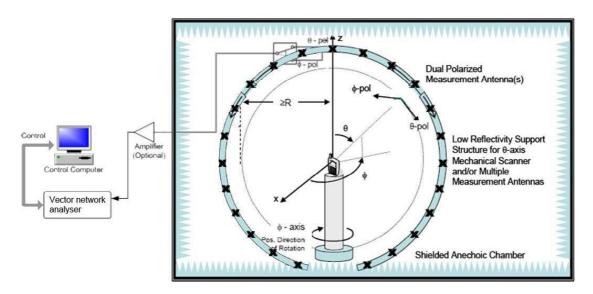
4.1 Test Condition

Environment	Selected Values During Tests			
Environment - Parameter	Ambient Pressure (KPa)	Temperature (°C)	Voltage	Relative Humidity (%)
Normal Temperature, Normal Voltage (NTNV)	100 to 102	19 to 25	N/A	45 to 55

4.2 Test Equipment List

Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
Vector Network	Agilopt	E5071C	MY46103472	2019.02.28	2020.02.27
Analyzer	Agilent	E3071C	101140103472	2019.02.26	2020.02.27
SG24 Multi-probe			1101055		
Antenna Measurement	SATIMO	SG24 - L	1101855-	2018.06.22	2020.06.21
System			0001		

4.3 Test Setup





ANNEX A TEST RESULTS

A.1 Gain and Efficiency

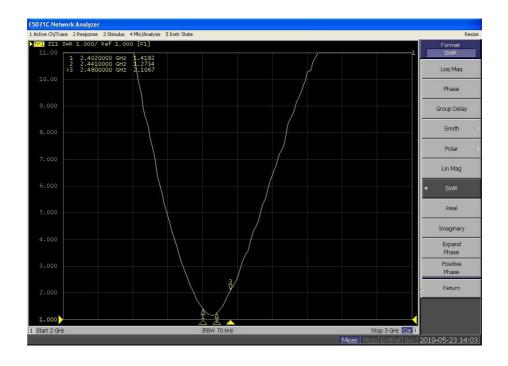
Frequency	Gain (dBi)	Efficiency (%)
2400MHz	2.11	67
2402MHz	2.25	67
2404MHz	2.37	67
2406MHz	2.49	67
2408MHz	2.58	67
2410MHz	3.00	68
2412MHz	2.62	68
2414MHz	2.60	68
2416MHz	2.57	68
2418MHz	2.51	69
2420MHz	2.43	69
2422MHz	2.35	69
2424MHz	2.37	69
2426MHz	2.28	70
2428MHz	2.27	70
2430MHz	2.27	69
2432MHz	2.28	69
2434MHz	2.25	69
2436MHz	2.20	69
2438MHz	2.15	68
2440MHz	2.10	68
2442MHz	2.07	68
2444MHz	2.03	68
2446MHz	1.99	67
2448MHz	1.98	68
2450MHz	2.00	68
2452MHz	2.00	68
2454MHz	2.01	68
2456MHz	2.00	67
2458MHz	2.05	68
2460MHz	2.09	67
2462MHz	2.11	67
2464MHz	2.15	66
2466MHz	2.14	66
2468MHz	2.15	65
2470MHz	2.15	65
2472MHz	2.14	64
2474MHz	2.12	64
2476MHz	2.10	63
L	I.	



2478MHz	2.02	63
2480MHz	1.94	62
2482MHz	1.88	61
2484MHz	1.79	61
2486MHz	1.65	60
2488MHz	1.53	59
2490MHz	1.45	59
2492MHz	1.36	58
2494MHz	1.25	58
2496MHz	1.19	57
2498MHz	1.17	57
2500MHz	1.14	57

A.2 VSWR

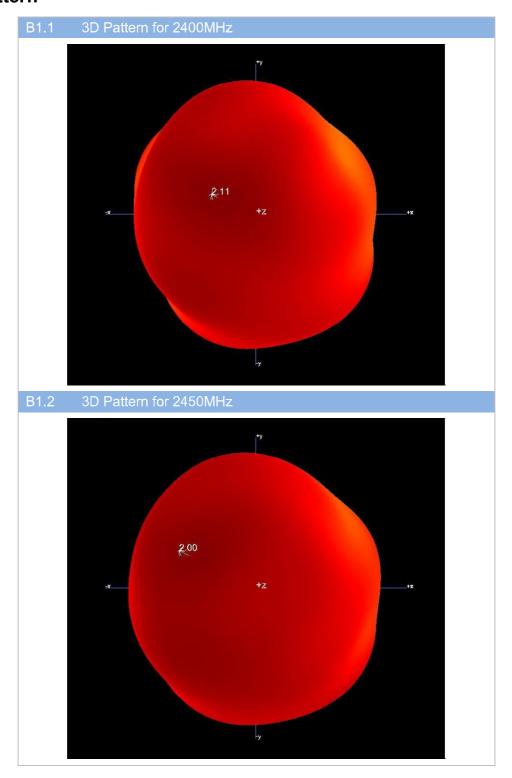
Frequency	VSWR
2402MHz	1.42
2441MHz	1.27
2480MHz	2.11



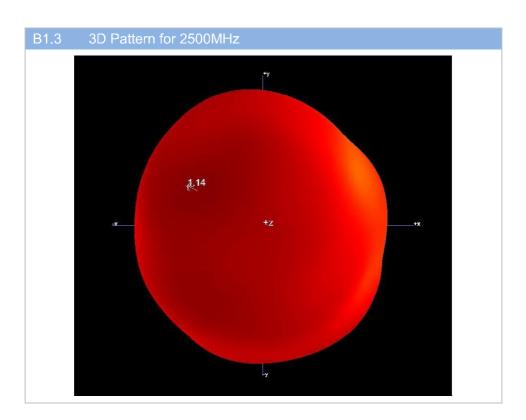


ANNEX B RADIATION PATTERN

B.1 3D Pattern

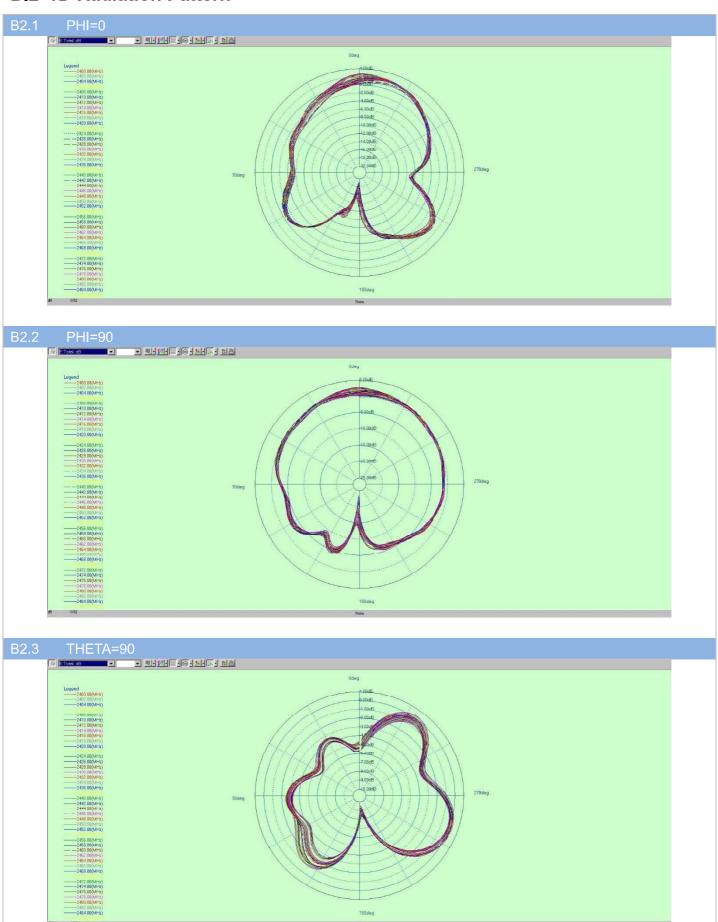






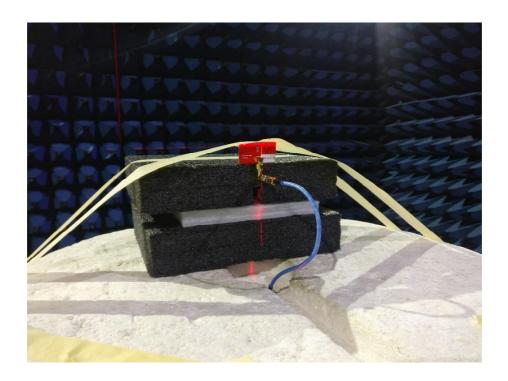


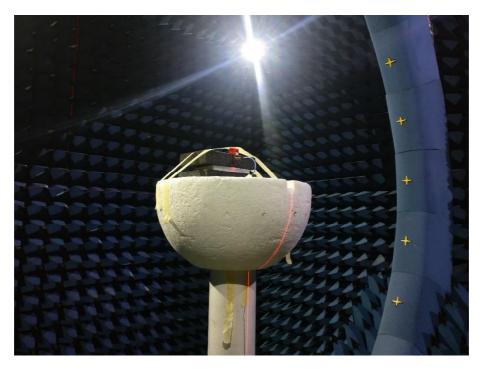
B.2 1D Radiation Pattern



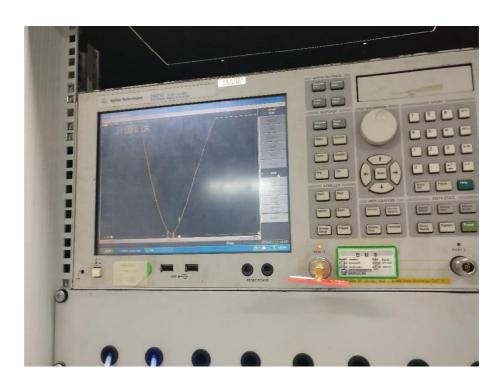


ANNEX C TEST SETUP PHOTO











ANNEX D EUT PHOTO

